## Notice of References Cited

Application/Control No. 10/716,462	Reexamination	Applicant(s)/Patent Under Reexamination MAO, JEAN-PIERRE		
Examiner	Art Unit			
Wutchung Chu	2616	Page 1 of 1		

## **U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	Α	US-2005/0220110	10-2005	Agarwal, Anil K.	370/392
*	В	US-2005/0207419	09-2005	Kohzuki et al.	370/392
*	С	US-2003/0118016	.06-2003	Kalkunte et al.	370/389
*	D	US-2002/0018474	02-2002	Assa et al.	370/395.71
*	E	US-2001/0043614	11-2001	VISWANADHAM et al.	370/469
*	F	US-7,031,343	04-2006	Kuo et al.	370/473
*	G	US-6,014,381	01-2000	Troxel et al.	370/395.52
*	Н	US-5,732,082	03-1998	Wartski et al.	370/395.6
*	1	US-5,303,302	04-1994	Burrows, Michael	713/161
*	J	US-6,430,184	08-2002	Robins et al.	370/392
	К	US			
ī	L	US-			
	М	US-			

## FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	0					
	Р					
	Q					
	R					
	s					
	Т					

## NON-PATENT DOCUMENTS

U	Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
-	
V	
w	
x	
	V

<sup>\*</sup>A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)

Dates in MM-YYYY format are publication dates. Classif ications may be US or foreign.